

Source	Syst. uncertainties	Effect on x-section measurement ttW	Effect on x-section measurement ttZ
Luminosity	6.2%	7-10%	8-14%
Jet Energy Scale/Resolution	1-6%	$\leq 1\%$	$< 1\%$
Trigger	2-5%	4-7%	3-6%
BTagging	1-8%	2-6%	3-6%
PU modeling	1%	$< 1\%$	$< 1\%$
Lepton Id., Eff.	7-10%	5-9%	7-16%
$\mu_R/\mu_F$ scale choice	2%	$< 1\%$	$< 1\%$
PDF choice	1%	$< 1\%$	$< 1\%$
Non-prompt background	30%,100%	12%	7-10%
WZ background cross section	20%	$< 1\%$	5-6%
ZZ background cross section	20%	-	4%
Charge mis-identification	20%	2%	-
Rare SM bkg	50%	5%	1-2%
ttH/tZq bkg	25%	2%	0-6%
Stat nonprompt	5-50%	8%	5%
Stat rare SM processes	20-100%	5%	3%
Total	-	23%	20%